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“Knowledge is such a treasure which cannot be stolen”

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Indian Standard

INDUCTOR AND TRANSFORMER CORES FOR TELECOMMUNICATIONS
Generic Specification

UDC 621.318.134.042.1 : 621.314.21

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BUREAU OF INDIAN STANDARDS
MANAK BHAVAN, 9 BAHADUR SHAH ZAFAR MARG
NEW DELHI 110002

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Indian Standard

INDUCTOR AND TRANSFORMER CORES FOR TELECOMMUNICATIONS
Generic Specification

National Foreword

This Indian Standard (Part 1), which is identical with IEC Pub 723-1 (1982)/QC 250000 'Inductor and transformer cores for telecommunications: Part 1 Generic specification', issued by the International Electrotechnical Commission (IEC), was adopted by the Bureau of Indian Standards on 7 September 1988 on the recommendation of the Magnetic Components and Ferrite Materials Sectional Committee (LTDC 13) and approval of the Electronics and Telecommunication Division Council.

Wherever the words 'International Standard' appear, referring to this standard, they should be read as 'Indian Standard'.

This standard is intended primarily for use under the IECQ System. A regular Indian Standard for this component could be different, identical or similar to this standard.

Cross Reference

In this Indian Standard, the following International Standards are referred to. Read in their respective place the following:

International Standard	*Corresponding Indian Standard*
IEC Pub 205 Calculations of the effective parameters of magnetic piece parts	IS : 7616-1974 Guide for calculation of the effective parameters of magnetic piece parts
IEC Pub 226 Dimensions of cross-cores (X-cores) made of ferromagnetic oxides and associated parts	IS : 7489-1974 Dimensions of cross-cores (X-cores) made of ferro-magnetic oxides and associated parts
IEC Pub 410 Sampling plans and procedures for inspection by attributes	IS : 10673-1983 Sampling plans and procedures for inspection by attributes for electronic items
IEC QC 001001(1981) Basic rules of the IEC quality assessment system for electronic components (IECQ)	IS QC 001001:1988 Basic rules of the IEC quality assessment system for electronic components (IECQ)
IEC QC 001002(1981) Rules of procedure of the IEC quality assessment system for electronic components (IECQ), sections 1 and 2	IS QC 001002:1988 Rules of procedure of the IEC quality assessment system for electronic components (IECQ)

International Standard	*Corresponding Indian Standard*
ISO 3 Preferred number — Series of preferred numbers	IS : 1076 Preferred numbers IS : 1076 (Part 1)-1985 Series of preferred numbers (*second revision*)
ISO 497 Guide to the choice of series of preferred numbers and of series containing more rounded values of preferred numbers	IS : 1076(Part 3)-1975 Guide to the choice of series of preferred numbers and of series containing more rounded values of preferred numbers (*second revision*)
ISO 1000 SI units and recommendations for the use of their multiples and of certain other units.	IS : 10005-1985 SI units and recommendations for the use of their multiples and of certain other units (*first revision*)

The Technical Committee responsible for the preparation of this standard has reviewed the provisions of the following IEC Standards and has decided that these are acceptable for use in conjunction with the this standard:

IEC Pub 27 Letter symbols to be used in electrical technology

IEC Pub 50 International electrotechnical vocabulary (including Chapter 901 : Magnetism)

IEC Pub 68-1 Basic environmental testing procedures, Part 1 General

IEC Pub 117 Recommended graphical symbols

IEC Pub 133 Dimensions for pot-cores made of ferromagetic oxides and associated parts

IEC Pub 367 Cores for inductors and transformers for telecommunications :

IEC Pub 367-1 Part 1 Measuring methods

IEC Pub 367-2 Part 2 Guides for the drafting of performance specifications

IEC Pub 367-2A First supplement to Pub 367-2(1974)

IEC Pub 424 Guide to the specification of limits for physical imperfections of parts made from magnetic oxides

IEC Pub 431 Dimensions of square cores (RM-cores) made of magnetic oxides and associated parts

IEC Pub 525 Dimensions of toroids made of magnetic oxides or iron powder

Only the English Langauge text in the International standard has been retained while adopting it in this Indian Standard.

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SECTION ONE – SCOPE

1. Scope

This generic specification lists the procedures to be used in the quality assessment of inductor and transformer cores for telecommunications, and the tests and measuring methods which may be selected by the appropriate sectional and blank detail specifications for these components. This specification prescribes the rules for writing blank detail specifications, and also gives the relevant units, symbols and terminology.

The components which are the subject of this specification are magnetic cores, mainly made of magnetic oxides or metallic powders, used in linear inductors and transformers for telecommunication equipment and electronic equipment employing similar techniques.

Further information on the test methods, the conditions under which they should be carried out and the precautions which should be observed in their use, are given in IEC Publication 367-1.

SECTION TWO – GENERAL

2. Document system

2.1 *Order of precedence*

Where any discrepancies occur for any reasons, documents shall rank in the following order of authority:

- the detail specification;
- the sectional specification;
- the generic specification;
- the basic specifications and other documents to which reference is made.

The same order of precedence shall apply to equivalent national documents.

2.2 *Related documents*

IEC Publications:

Publications Nos. 27:	Letter Symbols to be Used in Electrical Technology.
50:	International Electrotechnical Vocabulary (incl. Chapter 901: Magnetism).

68-1: Basic Environmental Testing Procedures. Part 1: General.

117: Recommended Graphical Symbols.
133: Dimensions for Pot-cores Made of Ferromagnetic Oxides and Associated Parts.
205: Calculation of the Effective Parameters of Magnetic Piece Parts.
226: Dimensions of Cross Cores (X-cores) Made of Ferromagnetic Oxides and Associated Parts.
367-1: Cores for Inductors and Transformers for Telecommunications, Part 1: Measuring Methods.
367-2: Part 2: Guides for the Drafting of Performance Specifications.

367-2A: First supplement to Publication 367-2 (1974).
410: Sampling Plans and Procedures for Inspection by Attributes.
424: Guide to the Specification of Limits for Physical Imperfections of Parts made from Magnetic Oxides.
431: Dimensions of Square Cores (RM-cores) Made of Magnetic Oxides and Associated Parts.
525: Dimensions of Toroids Made of Magnetic Oxides or Iron Powder.
QC 001001 (1981): Basic Rules of the IEC Quality Assessment System for Electronic Components (IECQ).
QC 001002 (1981): Rules of Procedure of the IEC Quality Assessment System for Electronic Components (IECQ). Sections 1 and 2.

ISO publications:

ISO Standards 3: Preferred numbers—Series of preferred numbers.
497: Guide to the choice of series of preferred numbers and of series containing more rounded values of preferred numbers.
1000: SI units and recommendations for the use of their multiples and of certain other units.

3. Units, symbols and terminology

3.1 *General*

Units, graphical symbols, letter symbols and terminology shall, whenever possible, be taken from the following documents:

IEC Publication 27;
IEC Publication 50;
IEC Publication 117;
ISO Standard 1000.

IEC Publications 367-1 and 367-2 contain additional terminology and letter symbols applicable to inductor and transformer cores.

3.2 *Multiples and sub-multiples of units*

Equations are given for coherent SI units only. In detail specifications, multiples and sub-multiples will normally be used as given in Note 4 to Clause 2 of IEC Publication 367-2. The standard symbols for quantities used in the equations are defined in Note 5 to Clause 2 of IEC Publication 367-2.

4. Standard and preferred values

4.1 *Dimensions*

The dimensions of inductor and transformer cores shall be in accordance with IEC publications. Where the detail specification makes reference to the relevant IEC publication, it shall mention the issue number and year and any valid amendments and supplements.

4.2 *Inductance factor*

For cores with an air-gap, the nominal value of the inductance factor shall be numerically equal to one of the terms in a series specified in ISO Standard 497.

Note. — The R5 series of ISO Standard 497 is preferred.

For cores with a separable adjusting device, the nominal value applies when the adjustor has been removed. For cores with inseparable adjusting devices, the minimum value of the inductance factor shall be taken as the nominal value.

5. Effective parameters

At least two of the five effective parameters and core factors as defined in IEC Publication 205 shall be given for each core in its detail specification. The values of effective parameters to be used for quality assessment shall be those appended to the dimensional standard for the appropriate core tvpe.

Note. — The manufacturers may indicate in their catalogues more precise values than those indicated in the relevant detail specification: these should be within the minimum and maximum limits which can be derived from the dimensions specified therein.

SECTION THREE — QUALITY ASSESSMENT PROCEDURES

6. Primary stage of manufacture

For the purpose of specifications for inductor and transformer cores made of magnetic oxides or of metallic powders, the primary stage is the final compacting of the powder into a solid form before sintering.

7. Sampling procedure

When use is made of IEC Publication 410 for attribute testing, the unit of product is as stated in the relevant test method or in the detail specification. Unless otherwise specified, the Acceptable Quality Level (AQL) shall refer to the percentage of defectives.

8. Inspection for qualification approval

To obtain qualification approval, the manufacturer shall produce test evidence of conformance to the requirements of the detail specification on three consecutive lots for lot-by-lot inspection and on one lot for periodic inspection. Normal inspection shall be used: for lot-by-lot inspection, a sampling plan with an acceptance number of not less than 1 shall be used.

Alternatively, a special sample may be drawn of cores of the same shape, size and material. This sample shall be subjected to all the tests in Group 0 of the qualification test schedule given in the detail specification. It shall then be split up into sub-samples as indicated in the sectional specification, each sub-sample being subjected to one of the other groups of the qualification test schedule.

9. Quality conformance inspection

The detail specification shall prescribe the tests to be carried out on each inspection lot and those to be carried out for periodic inspection, in accordance with the rules of the appropriate sectional specification.

For continuous production of cores, an inspection lot is defined as all cores of the same shape and size, produced from one batch of material powder, pressed and sintered using essentially the same process and irrespective of the inductance factor of the finished product. The last manufacturing stage of the lot shall be carried out within a stated period, which should normally not exceed one week.

The samples drawn from such an inspection lot shall contain proportional parts of each inductance factor where this can have an influence on the test result.

Alternatively, when the cores are placed in an intermediate store before grinding of the air-gap, the above lot definition is valid up to that stage. For the remaining manufacturing stages, cores of similar shape and size but from different inspection lots before storing, may be aggregated into one inspection lot after the final manufacturing stages on condition that:

- the core lots were released against the detail specification requirements appropriate to the cores in the ungapped stage before placing them in the intermediate store;
- all cores were pressed and sintered using essentially the same process;
- the final manufacturing stage has taken place within a given period for an inspection lot, which should normally not exceed one week;
- both the original (before intermediate storing) and the final inspection lots can be traced.

The sample drawn from such an inspection lot shall contain proportional parts of the original lots and, as far as this can have an influence on the test results, of each inductance factor.

10. Delayed delivery

In principle, the rule of procedure on delayed delivery is not applicable to magnetic cores consisting of ferrite material or metallic powder only.

Unless otherwise specified in the detail specification, cores with a glued-in fixed part of the adjusting device held in the manufacturer's or distributor's store for a period such that 24 months have elapsed since the release for delivery of the inspection lot, shall be re-examined for fixing of this device as indicated under Group C testing but to an inspection level S4 (normal testing). In this case, the inspection lot may contain all cores having fixed parts of the same design, material and size which have been glued-in by the same technique.

Once such an inspection lot has been satisfactorily re-inspected, its quality is reassured for a further 24 months.

11. Certified records of released lots

Certified records of released lots, when prescribed in the relevant specification and requested by the purchaser, shall contain, as a minimum, attribute information for each test of the lot-by-lot inspection.

The contents of these certified records shall comply with the requirements given in the relevant clause of the Rules of Procedure of the IEC Quality Assessment System for Electronic Components.

SECTION FOUR — TESTS AND MEASURING METHODS

12. Visual examination and dimensions

12.1 *Visual examination*

The condition, workmanship and finish shall be satisfactory as determined by visual examination. The permissibility of any physical imperfections shall be judged on the basis of IEC Publication 424. The percentage of permissible chipping shall be stated in the detail specification.

12.2 *Marking*

The marking shall be as specified in the detail specification and it shall be legible as determined by visual examination.

12.3 *Primary dimensions*

The dimensions indicated in the detail specification as primary dimensions shall be checked and shall comply with the values stated in the detail specification. When gauges are specified these shall be used in accordance with the prescribed gauging procedure and acceptance or rejection of specimens is decided solely on the result of that procedure.

12.4 *Secondary dimensions*

The dimensions in the detail specification not indicated as primary dimensions shall be checked and they shall comply with the values stated in the detail specification.

13. Electrical tests and measuring methods

13.1 *General*

The test and measuring methods and the precautions for measurement shall be in accordance with IEC Publication 367-1.

In those cases where the measuring frequency or frequencies for the characteristics to be specified are not dictated by the application or by other considerations, they should be chosen from the series in Sub-clause 4.4 of IEC Publication 367-2, i.e.:

1 - 3 - 10 ... kHz

13.2 *General conditions*

The environmental conditions shall be in accordance with Clause 3 of IEC Publication 367-1.

13.3 *Inductance measurement*

13.3.1 The inductance factor or some other inductance parameter of the core shall be measured in accordance with Sub-clause 7.3 of IEC Publication 367-1, taking into account the precautions laid down in Clause 4 of that same publication.

The approximate, or the maximum, measuring frequency f and the maximum permissible peak effective flux density $\hat{B}_e$ during measurement shall be stated in the detail specification. The maximum sinusoidal r.m.s. voltage U to be applied to the measuring coil may be calculated from:

$$U = 4.44 f N A_e \hat{B}_e$$

where:

N = number of turns on the measuring coil
A_e = effective cross-sectional area of the core

13.3.2 The inductance factor so measured shall correspond to the rated value within the tolerance specified.

13.4 *Disaccommodation*

13.4.1 Unless otherwise specified, the disaccommodation factor shall be determined in accordance with Clause 8 of IEC Publication 367-1 using the electrical (capacitor discharge) method of magnetic conditioning, and the measuring conditions during inductance measurement shall be as specified for Sub-clause 13.3.1.

13.4.2 The disaccommodation or the disaccommodation factor shall not exceed the value specified in the detail specification.

13.5 *Variation of permeability with temperature*

13.5.1 Unless otherwise stated, the mean temperature factor or the mean temperature coefficient shall be specified and measured according to Clause 9, method B, of IEC Publication 367-1 between the reference temperature of 25 °C and one or more temperatures stated in the detail specification. The approximate or maximum measuring frequency shall be as stated in the detail specification.

13.5.2 The deviation at each measuring temperature of measured inductance from its value measured at reference temperature shall not exceed the specified limits.

13.5.3 When absolute limits of temperature factor or coefficient are specified, the method and requirements of Sub-clauses 13.5.1 and 13.5.2 apply and the detail specification shall specify several measuring temperatures within each range over which one value of temperature factor or coefficient applies. In case of doubt, the curve of inductance change versus temperature should be plotted in accordance with Sub-clause 3.2 and possibly Clause 4 of Appendix E of IEC Publication 367-1 for one or more cores from a sample. If necessary, the measurement shall be repeated with additional measurement temperatures.

13.5.4 When, in addition, limits on the shape of the curve are specified, methods A or B of Clause 9 of IEC Publication 367-1 should preferably be used and the curve of inductance change versus temperature plotted for each specimen. Apart from meeting the requirements of Sub-clause 13.5.2 (which may be checked immediately on the curve by means of limit lines drawn in accordance with Sub-clause 3.2 and possibly Clause 4 of Appendix E of IEC Publication 367-1), the slope at any point of the curve shall comply with the requirements stated in the detail specification.

13.6 *Range of inductance adjustment*

13.6.1 The measurement shall be carried out as specified in Clause 10 of IEC Publication 367-1.

13.6.2 The measured upper limit of the adjustment range shall be not less than the value specified in the detail specification. The measured lower limit of the adjustment range shall be not greater than the value specified in the detail specification.

There shall be no change in the sign of the slope between the specified upper and lower limits of the adjustment range.

13.7 *Residual and eddy current losses*

13.7.1 The specified loss parameter or quality factor shall be measured in accordance with Sub-clause 11.1.4 of IEC Publication 367-1, taking into account the precautions as specified in Clause 5 of that same publication. The detail specification shall specify one or more measuring frequencies; during measurement the frequency shall not deviate by more than ±2% from the specified value. The maximum permissible peak effective flux density shall also be stated in the detail specification, unless its maximum is equal to that specified for the inductance measurement according to Sub-clause 13.3.1.

13.7.2 The measured loss parameter shall not exceed, or the measured quality factor shall be not less than, the value stated in the detail specification.

13.8 *Hysteresis loss*

13.8.1 The specified loss parameter shall be measured in accordance with Sub-clause 11.1.5 of IEC Publication 367-1 taking into account the precautions as specified in Clause 5 of that same publication. The detail specification shall specify the measuring frequency and two values of the peak effective flux density at which the measurement shall be made.

13.8.2 The measured loss parameter shall not exceed the value stated in the detail specification.

13.9 *Third harmonic distortion*

13.9.1 The third harmonic material constant shall be measured in accordance with one of the methods specified in Clause 12 of IEC Publication 367-1. The detail specification shall state the fundamental frequency and the peak flux density for this measurement and shall give details of the measuring coil to be used.

13.9.2 The measured third harmonic material constant shall not exceed the value stated in the detail specification.

13.10 *Magnetic shock sensitivity*

13.10.1 The magnetic shock sensitivity shall be measured in accordance with Clause 13 of IEC Publication 367-1. Details of the test coil, which is also used for the measurement of inductance during this test, shall be given in the detail specification. Unless otherwise stated, the frequency during the inductance measurements shall be as specified in Sub-clause 13.3.1.

13.10.2 The measured magnetic shock sensitivity shall not exceed the value stated in the detail specification.

13.11 *Contribution of the adjusting device to the core instability*

13.11.1 The determination of the contribution of the adjusting device to the core instability shall be made in accordance with Clause 14 of IEC Publication 367-1. The detail specification shall state the approximate frequency for the inductance measurement.

13.11.2 The measured contribution of the adjusting device to the core instability shall not exceed the value stated in the detail specification.

13.12 *Influence of a static magnetic field*

No test requirements are specified.

Note. – Clause 15 of IEC Publication 367-1 gives methods of measurement for the influence of a static magnetic field.

14. Mechanical tests

14.1 *Compressive strength of cores*

A force equal to twice the specified clamping force, or as otherwise specified in the detail specification, shall be applied for 1 min to the core in the same way as specified for clamping (see Sub-clause 4.3 of IEC Publication 367-1) but without exerting the transient overforce. The load shall be increased from zero to the specified value in about 10 s. There shall be no mechanical damage.

14.2 *Adjusting devices*

14.2.1 *Expulsion force*

The force specified in the detail specification shall be applied for 10 s to the fixed part of the adjusting device in a direction most likely to result in separation of the fixed part from the core. The application of the force to the fixed part shall be distributed over a sufficient surface area so as not to give rise in itself to damage of the said part. The force shall be increased from zero to the specified value in about 10 s.

The core shall not be damaged and the fixed part of the adjusting device shall not be loosened from the core nor be damaged.

14.2.2 *End-stop torque*

For screw-type adjusting devices, the torque specified in the detail specification shall be applied for 10 s to the adjuster in the fully screwed-in position. The torque shall be increased from zero to the specified value in about 1 s.

Neither the core nor the adjusting device shall be damaged and the fixed part of the adjusting device shall not be loosened from the core.

14.2.3 *Adjusting torque*

No test requirements are specified.

SECTION FIVE — BLANK DETAIL SPECIFICATIONS

15. General

The basic data detailed in the following clauses shall appear in detail specifications. Appendices A and B of this standard give the layouts preferred for the presentation of these data.

Appendix A shows how the general data necessary to identify the specification and the cores are presented. It also shows where such additional data as are required for the proper ordering and release of cores can be included. The numbers in brackets in the proforma refer to data specified in Items 1 to 9 which are listed in Clauses 16 and 17.

Appendix B shows the manner in which the test schedule and inspection requirements are presented.

The sectional specification appropriate to the sub-family shall prescribe in detail the necessary data to be included.

16. Identification of the detail specification

The identification of the detail specification shall include:

1) Name of the national standards organization under whose authority the detail specification is drafted.
2) IEC number of the relevant blank detail specification.
3) Number and issue status of the national generic specification.
4) National number of the detail specification, date of issue and any other information required by the national system.

17. Identification of the core

The identification of the core shall include:

5) A short description of the type of core, e.g.: “Ferrite pot core 18 mm × 11 mm”.
6) A short description of the class, i.e. the main electromagnetic characteristics of the core material.
7) An outline drawing with main dimensions and/or reference to the appropriate national or international documents for outlines. The drawing with dimensions may also be given in an appendix to the detail specification.
8) The application or group of applications covered by the (complete) blank detail specification, for example, “For use in inductors and tuned transformers in equipment for telecommunication, industrial, professional and military applications”.

9) Reference data giving information on the most important properties of cores, which allow comparison between the various core types intended for the same or similar applications.

18. Supplementary information

Detail specifications shall include such supplementary information specific to the core, or range of cores, which they cover, such as:

- marking;
- ordering information;
- related documents directly referred to in the detail specification;
- requirements for certified test records, when applicable;
- lot definition in connection with structural similarity.

19. Test schedule

The test schedule to be prescribed in the detail specification shall be selected from those included in the appropriate sectional specification.

APPENDIX A

FORMAT FOR THE FIRST PAGE OF DETAIL SPECIFICATIONS

<table>
<tr><td>(1)</td><td>Page
(2)
of</td></tr>
<tr><td>Core of assessed quality in accordance with
(3)</td><td>(4)</td></tr>
<tr><td colspan="2">Detail specification for (5)
Class: (6)</td></tr>
<tr><td>(7)</td><td>(8)</td></tr>
<tr><td colspan="2">(9)</td></tr>
<tr><td colspan="2">See the relevant Qualified Parts List for availability of cores made to this detail specification.</td></tr>
</table>

APPENDIX B

FORMAT FOR THE TEST SCHEDULE

<table>
<tr><td colspan="3">Groups A and B inspection (lot-by-lot)</td><td colspan="2">Test schedule No.</td><td>Page of</td></tr>
<tr><td rowspan="2">Sub-group</td><td rowspan="2">D or ND
(Note 1)</td><td colspan="2">Inspection (Note 2)</td><td colspan="2" rowspan="2">Remarks</td></tr>
<tr><td>IL</td><td>AQL</td></tr>
<tr><td>Clause number of generic specification (IEC Publication 723-1) and name of test</td><td colspan="3">Conditions of test</td><td colspan="2">Performance requirements</td></tr>
</table>

<table>
<tr><td><i>Sub-group A1</i></td><td></td><td></td><td></td><td></td></tr>
<tr><td></td><td colspan="3"></td><td></td></tr>
<tr><td><i>Sub-group A2</i></td><td></td><td></td><td></td><td></td></tr>
<tr><td>etc.</td><td colspan="3"></td><td></td></tr>
</table>

<table>
<tr><td colspan="4">Group C inspection (periodic)</td><td colspan="2">Test schedule No.</td><td>Page of</td></tr>
<tr><td rowspan="2">Sub-group</td><td rowspan="2">D or ND
(Note 1)</td><td colspan="3">Inspection (Note 3)</td><td colspan="2" rowspan="2">Remarks</td></tr>
<tr><td>p</td><td>n</td><td>c</td></tr>
<tr><td>Clause number of generic specification (IEC Publication 723-1) and name of test</td><td colspan="4">Conditions of test</td><td colspan="2">Performance requirements</td></tr>
</table>

<table>
<tr><td><i>Sub-group C1</i></td><td></td><td></td><td></td><td></td><td></td></tr>
<tr><td>etc.</td><td colspan="4"></td><td></td></tr>
</table>

Notes 1. — D = destructive test;
ND = non-destructive test.
2. — IL = inspection level;
AQL = acceptable quality level (see IEC Publication 410).
3. — p = interval in months between periodic tests;
n = number of specimens to be subjected to each test;
c = number of defectives allowed in each sample.